



## Growth of Semipolar III-V Nitride Films with Lower Defect Density

Tech ID: 23649 / UC Case 2006-422-0

### BRIEF DESCRIPTION

A novel method for growing high quality semipolar III-V nitride based optoelectronic devices.

### BACKGROUND

Current nitride technology for electronic and optoelectronic devices employs nitride films grown in the polar c-direction. Unfortunately, the structure of III-nitride based devices suffers from the undesirable quantum-confined Stark effect (QCSE), due to the strong electric fields and polarization effects along the c-direction. While growing devices on nonpolar planes of the crystal seems advantageous, growth of nonpolar nitrides remains challenging and has not yet been widely adopted in the industry.

### DESCRIPTION

Researchers at the University of California, Santa Barbara have developed a novel method for growing high quality semipolar III-V nitride based optoelectronic devices. This includes growing an active layer on suitable material with faceted surfaces, which are typically semipolar planes, and a method for fabricating the faceted surfaces. The use of these growth techniques results in semipolar light emitting layers with a low defect density through reduction of the polarization effects in GaN devices. Furthermore, these layers may be grown using commonly used techniques including, MOCVD, MBE, or HPVE.

### ADVANTAGES

- ▶ Lower defect density
- ▶ Higher quality devices
- ▶ Uses widely adopted growth techniques

### APPLICATIONS

### CONTACT

Pasquale S. Ferrari  
[ferrari@tia.ucsb.edu](mailto:ferrari@tia.ucsb.edu)  
tel: .

### INVENTORS

- ▶ [DenBaars, Steven P.](#)
- ▶ [Kaeding, John F.](#)
- ▶ [Nakamura, Shuji](#)
- ▶ [Sharma, Rajat](#)
- ▶ [Speck, James S.](#)
- ▶ [Zhong, Hong](#)

### OTHER INFORMATION

#### KEYWORDS

nitride films, indssl, indbulk

#### CATEGORIZED AS

- ▶ [Engineering](#)
- ▶ [Optics and Photonics](#)
  - ▶ [All Optics and Photonics](#)
- ▶ [Semiconductors](#)
  - ▶ [Design and Fabrication](#)

#### RELATED CASES

[2006-422-0](#)

- ▶ Optoelectronic devices
- ▶ High power electronic devices

## PATENT STATUS

Country	Type	Number	Dated	Case
United States Of America	Issued Patent	8,203,159	06/19/2012	2006-422
United States Of America	Issued Patent	7,858,996	12/28/2010	2006-422

## ADDITIONAL TECHNOLOGIES BY THESE INVENTORS

- ▶ Etching Technique for the Fabrication of Thin (Al, In, Ga)N Layers
- ▶ Lateral Growth Method for Defect Reduction of Semipolar Nitride Films
- ▶ Vertical Cavity Surface-Emitting Lasers with Continuous Wave Operation
- ▶ Eliminating Misfit Dislocations with In-Situ Compliant Substrate Formation
- ▶ III-Nitride-Based Vertical Cavity Surface Emitting Laser (VCSEL) with a Dielectric P-Side Lens
- ▶ Aluminum-cladding-free Nonpolar III-Nitride LEDs and LDs
- ▶ Low-Cost Zinc Oxide for High-Power-Output, GaN-Based LEDs (UC Case 2010-183)
- ▶ Defect Reduction in GaN films using in-situ SiNx Nanomask
- ▶ Enhanced Light Extraction LED with a Tunnel Junction Contact Wafer Bonded to a Conductive Oxide
- ▶ Low Temperature Deposition of Magnesium Doped Nitride Films
- ▶ Transparent Mirrorless (TML) LEDs
- ▶ Improved GaN Substrates Prepared with Ammonothermal Growth
- ▶ Optimization of Laser Bar Orientation for Nonpolar Laser Diodes
- ▶ Method for Enhancing Growth of Semipolar Nitride Devices
- ▶ Ultraviolet Laser Diode on Nano-Porous AlGaIn template
- ▶ Improved Reliability & Enhanced Performance of III-Nitride Tunnel Junction Optoelectronic Devices
- ▶ Growth of Polyhedron-Shaped Gallium Nitride Bulk Crystals
- ▶ Nonpolar III-Nitride LEDs With Long Wavelength Emission
- ▶ Improved Fabrication of Nonpolar InGaIn Thin Films, Heterostructures, and Devices
- ▶ Growth of High-Quality, Thick, Non-Polar M-Plane GaN Films
- ▶ Method for Growing High-Quality Group III-Nitride Crystals
- ▶ Controlled Photoelectrochemical (PEC) Etching by Modification of Local Electrochemical Potential of Semiconductor Structure
- ▶ Oxyfluoride Phosphors for Use in White Light LEDs
- ▶ Technique for the Nitride Growth of Semipolar Thin Films, Heterostructures, and Semiconductor Devices
- ▶ (In,Ga,Al)N Optoelectronic Devices with Thicker Active Layers for Improved Performance
- ▶ Thermally Stable, Laser-Driven White Lighting Device
- ▶ MOCVD Growth of Planar Non-Polar M-Plane Gallium Nitride
- ▶ Methods for Fabricating III-Nitride Tunnel Junction Devices
- ▶ Low-Droop LED Structure on GaN Semi-polar Substrates
- ▶ Contact Architectures for Tunnel Junction Devices
- ▶ Semi-polar LED/LD Devices on Relaxed Template with Misfit Dislocation at Hetero-interface
- ▶ Semipolar-Based Yellow, Green, Blue LEDs with Improved Performance
- ▶ III-Nitride-Based Devices Grown On Thin Template On Thermally Decomposed Material
- ▶ III-Nitride Tunnel Junction LED with High Wall Plug Efficiency

- ▶ Tunable White Light Based on Polarization-Sensitive LEDs
- ▶ Cleaved Facet Edge-Emitting Laser Diodes Grown on Semipolar GaN
- ▶ Growth of High-Performance M-plane GaN Optical Devices
- ▶ Packaging Technique for the Fabrication of Polarized Light Emitting Diodes
- ▶ Improved Anisotropic Strain Control in Semipolar Nitride Devices
- ▶ Novel Multilayer Structure for High-Efficiency UV and Far-UV Light-Emitting Devices
- ▶ III-V Nitride Device Structures on Patterned Substrates
- ▶ Method for Increasing GaN Substrate Area in Nitride Devices
- ▶ High-Intensity Solid State White Laser Diode
- ▶ Nitride Based Ultraviolet LED with an Ultraviolet Transparent Contact
- ▶ GaN-Based Thermoelectric Device for Micro-Power Generation
- ▶ Limiting Strain-Relaxation in III-Nitride Heterostructures by Substrate Patterning
- ▶ LED Device Structures with Minimized Light Re-Absorption
- ▶ Growth of Planar Semi-Polar Gallium Nitride
- ▶ High-Efficiency and High-Power III-Nitride Devices Grown on or Above a Strain Relaxed Template
- ▶ UV Optoelectronic Devices Based on Nonpolar and Semi-polar AlInN and AlInGaN Alloys
- ▶ Defect Reduction of Non-Polar and Semi-Polar III-Nitrides
- ▶ III-Nitride Based VCSEL with Curved Mirror on P-Side of the Aperture
- ▶ Enhancing Growth of Semipolar (Al,In,Ga,B)N Films via MOCVD

